PATENT NUMBER and ISSUE DATE

U.S. UTILITY Patent Application

ISSUE FEE	A88	istant Exa	aminer			Print Claim fo
		lad			CLAIMS ALI	
OF ALLOWANCE	MAILED					
	* ***			0	S.DEPT. OF COMM, IPAT, & TM-P	TO-436L(Rev. 12-94
ser annealing appa	aratus	, , o.u				
TLE : Method for	manufacturing poly	vcrvstallin	e semicondus	YI	KI-0084 s and thin-film transis	
USC 119 conditions	net jed Examiners's intials	_		1	TTORNEY DOCKET	NO
oreign priority claimed		☐ yes ☐ ı	RESCIND		*	
G-PUB DO NOT	DUDUGU 🗇					
			,			•
JAPAN 2001-4718	LICATIONS VERI	FIED:				
** FOREIGN ADD	LICATIONS					
-						
·						
			المسادة المداد	. 00	, , , , , , , , , , , , , , , , , , , 	
	BEST	AVA	ILABLE	00	DV	
**CONTINUING	DATA VERIFIED	:				
, i vaka	nishi Shiro; Morimo	oto Yoshil	hiro;			. •
**APPLICANTS		Takashi; I	lmao Kazuhiro	; Wakita	Ken; Monzen Toshio	CEMAN OCO CONTRACTOR
:	02/22/2002	438	SUBCLASS 166	GAU 2812	EXAMIN	
10080424						

MOTIVE OF ALL	OWANCE MAILED								
			CLAIMS ALLOWED						
ISSUE FEE		Assistant Examiner	Total Claims		Print Claim for O.G				
Amount Due	Date Paid	-	DRAWING						
			Sheets Drwg. Figs.			Print Fig.			
TERMINAL DISCLAMER		Primary Examiner		L					
		PREPARED FOR ISSUE	Application Examiner						
)	WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.							
			(CRF)	<u>ыз ошу.</u> Г	70	D-POM			

(Attached in pocket on right inside flap)